

<b>Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10663901	KAKUHARI ET AL.
	Examiner Tran, Mai T	Art Unit 2129

Class	SubClass	Date	Examiner
706	16	09/12/2006	mtt
29	745, 747, 844, 851, 861	09/12/2006	mtt
72	21.4	09/12/2006	mtt

U.S. Patent and Trademark Office	Part of Paper No.: 09062006
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<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
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Notes	Date	Examiner
EAST (Please see search history printout)	08/01/2006	mtt
ACM Portal (Please see search history printout)	09/12/2006	mtt
Google (Please see search history printout)	09/12/2006	mtt
IEEE (Please see search history printout)	09/12/2006	mtt
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<b>Interference Searched</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
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US-PGPub, USPAT text search (Please see interference search printout)		9/12/2006	mtt
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